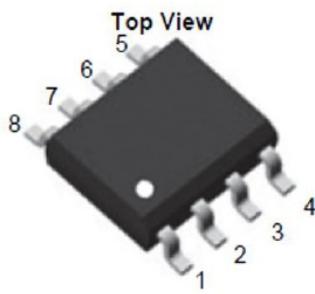
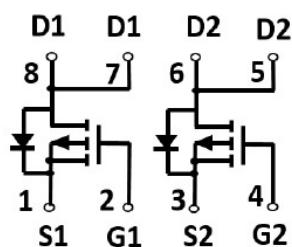
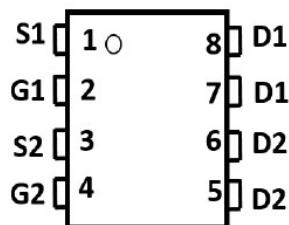


P-Channel Enhancement Mode Field Effect Transistor



SOP-8



Product Summary

- V_{DS} -30V
- I_D -7.1A
- $R_{DS(ON)}$ (at $V_{GS}=-10V$) <25mohm
- $R_{DS(ON)}$ (at $V_{GS}=-4.5V$) <40mohm
- 100% ∇V_{DS} Tested

General Description

- Trench Power LV MOSFET technology
- High density cell design for low $R_{DS(ON)}$
- High Speed switching

Applications

- Battery protection
- Load switching
- Power management

■ Absolute Maximum Ratings ($T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-source Voltage	V_{DS}	-30	V
Gate-source Voltage	V_{GS}	± 20	V
Drain Current	I_D	-7.1	A
Pulsed Drain Current ^A	I_{DM}	-20	A
Total Power Dissipation	P_D	2.5	W
		1.6	W
Thermal Resistance Junction-to-Ambient ^B	$R_{\theta JA}$	50	$^\circ\text{C}/\text{W}$
Junction and Storage Temperature Range	T_J, T_{STG}	-55~+150	$^\circ\text{C}$

■ Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Parameter						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-30			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0\text{V}$			-1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$			± 100	nA
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-1.0	-1.5	-2.5	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-7\text{A}$		20	25	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-5\text{A}$		30	40	
Diode Forward Voltage	V_{SD}	$I_{\text{S}}=-7\text{A}, V_{\text{GS}}=0\text{V}$			-1.2	V
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{\text{DS}}=-15\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$		1488		pF
Output Capacitance	C_{oss}			178		
Reverse Transfer Capacitance	C_{rss}			164		
Switching Parameters						
Total Gate Charge	Q_g	$V_{\text{GS}}=-10\text{V}, V_{\text{DS}}=-15\text{V}, I_{\text{D}}=-7.1\text{A}$		28.44		nC
Gate-Source Charge	Q_{gs}			5.25		
Gate-Drain Charge	Q_{gd}			5.17		
Reverse Recovery Charge	Q_{rr}	$I_F=-5\text{A}, dI/dt=100\text{A/us}$		5.3		ns
Reverse Recovery Time	t_{rr}			14		
Turn-on Delay Time	$t_{\text{D(on)}}$	$V_{\text{GS}}=-10\text{V}, V_{\text{DS}}=-15\text{V}, I_{\text{D}}=-7.1\text{A}, R_{\text{GEN}}=2.5\Omega$		10		ns
Turn-on Rise Time	t_r			44		
Turn-off Delay Time	$t_{\text{D(off)}}$			54		
Turn-off fall Time	t_f			58		

A. Pulse Test: Pulse Width $\leq 300\text{us}$, Duty cycle $\leq 2\%$.

B. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design, while $R_{\theta JA}$ is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.

■ Typical Performance Characteristics

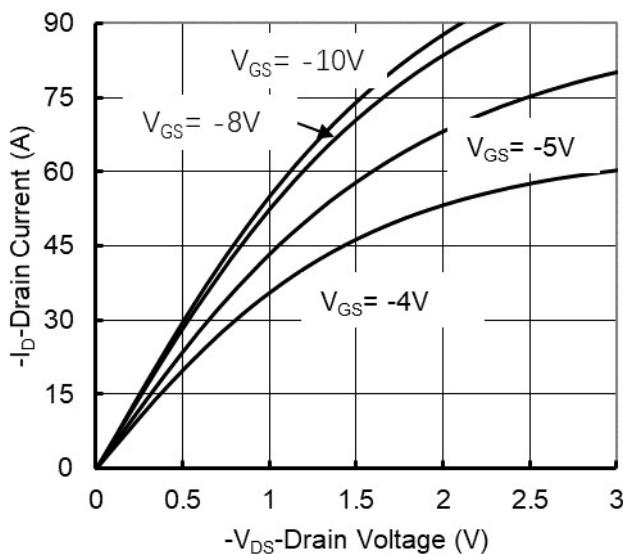


Figure 1. Output Characteristics

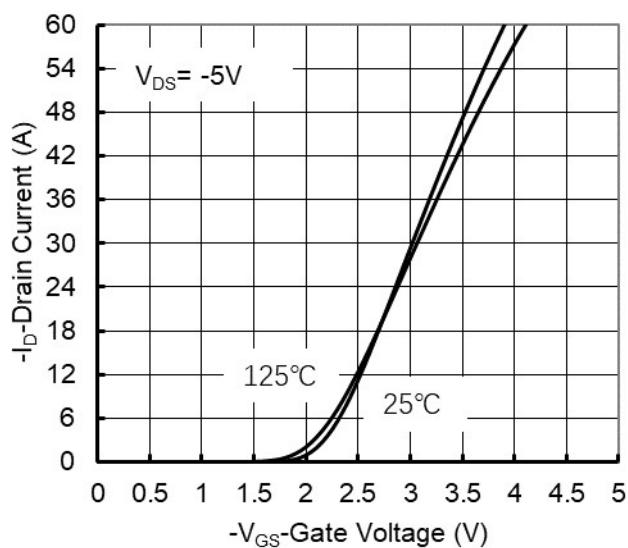


Figure 2. Transfer Characteristics

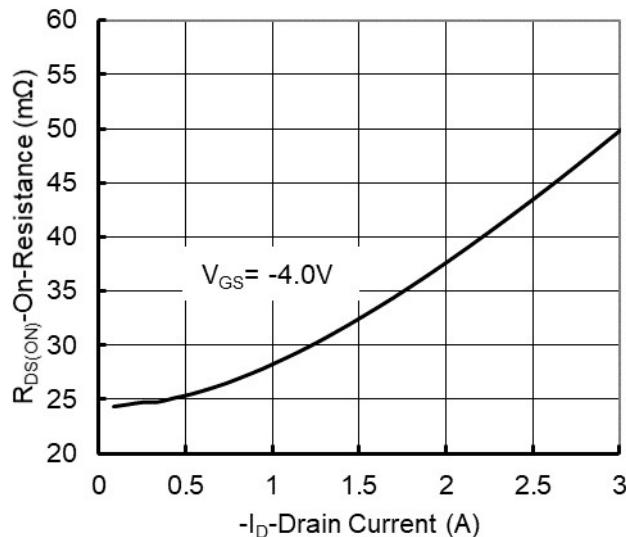


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

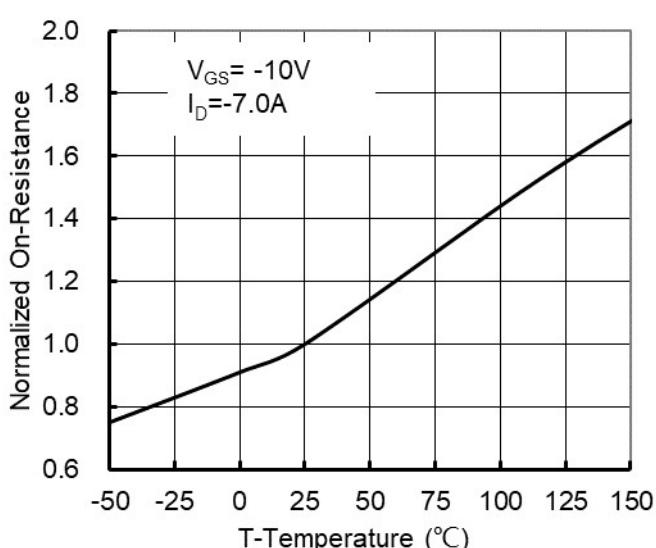


Figure 4. On-Resistance vs. Junction Temperature

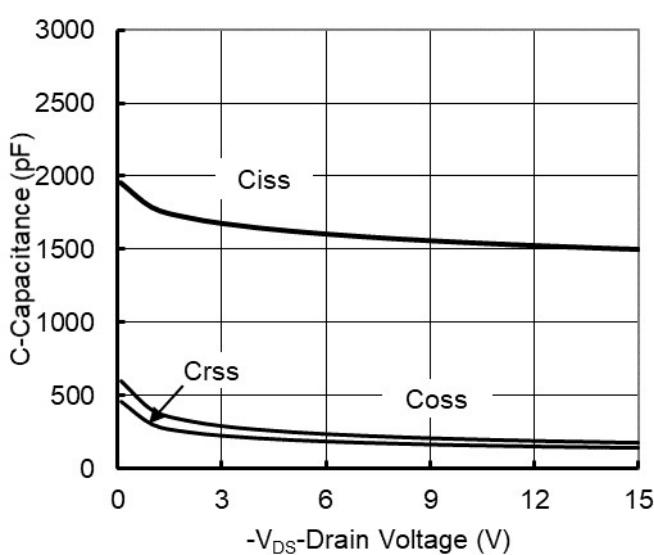


Figure 5. Capacitance Characteristics

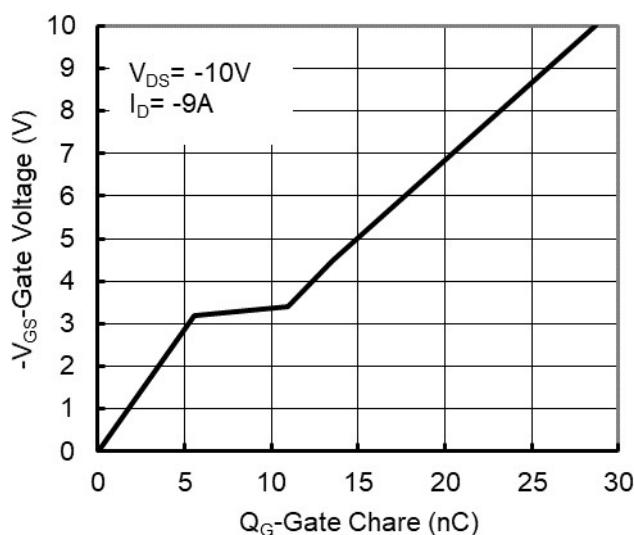


Figure 6. Gate Charge

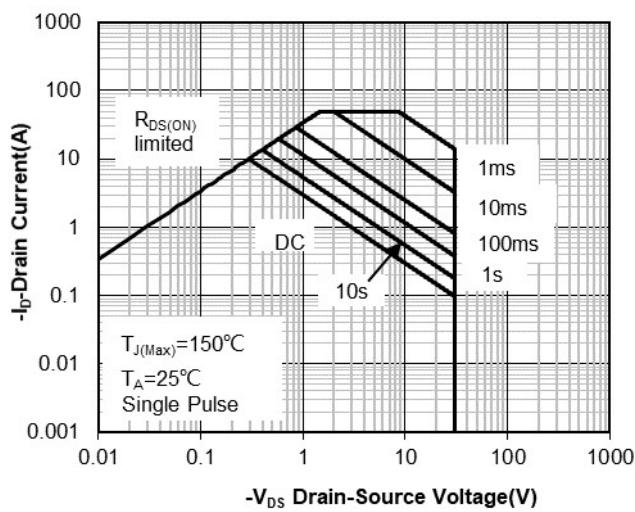


Figure 7. Safe Operation Area

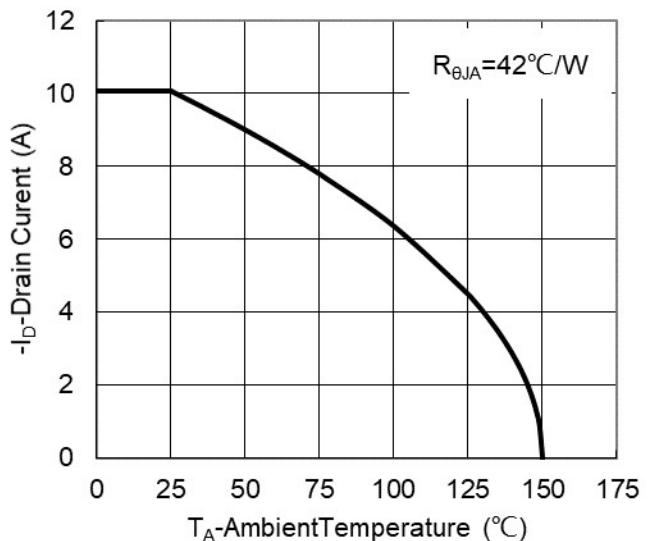
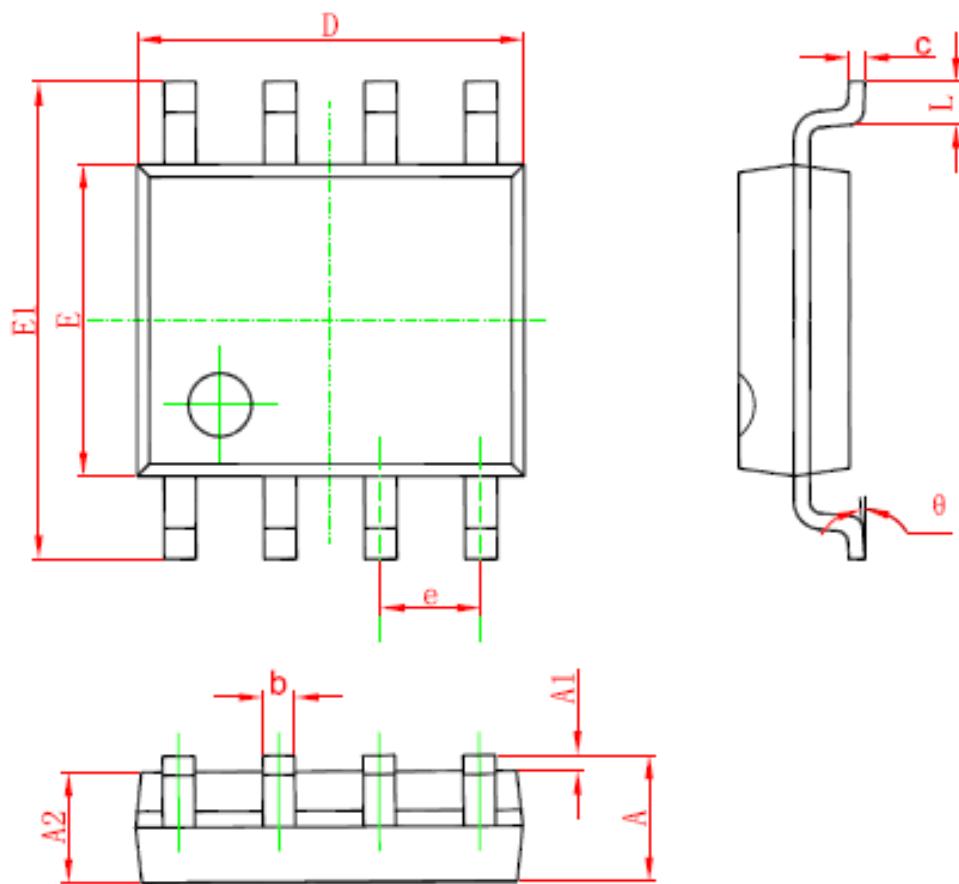


Figure 8. Maximum Continuous Drain Current
vs Ambient Temperature

■ SOP-8 Package information

Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270 (BSC)		0.050 (BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°